

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination CHON, HWA-SU	
		Examiner Nitin Patel	Art Unit 2629	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,020,945	02-2000	Sawai et al.	349/119
*	B	US-2006/0001800	01-2006	Sanelle et al.	349/096
*	C	US-7,060,333	06-2006	Takeuchi et al.	428/1.3
*	D	US-2001/0022632	09-2001	Umemoto et al.	349/12
*	E	US-6,559,834	05-2003	Murakami et al.	345/173
*	F	US-6,707,450	03-2004	Ahn et al.	345/173
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 5-173707	12-1991	Japan	Umezaki	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.